## INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) DEC 2 0 7004

ATTY DOCKET NO. SERIAL NO. US Div'l of 10/465,075

Naor WAINER et al.

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To be assigned

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	12	CH 471 392	15 Apr '69	SWITZERLAND					
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-	17	HE, Z. et al.; "Coplanar Grid Patterns and Their Effect on Energy Resolution of CdZnTe Detectors;" IEEE Nuclear Science Symposium and Medical Imaging Conference; Albuquerque, Mexico; 9-15 November 1997
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EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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